TES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

GEORGE VALLIATH

SERIAL NO: 09 921,895

GAU:

2823

FILED:

AUGUST 6, 2001

EXAMINER: COLEMAN, W

FOR:

STRUCTURE AND METHOD FOR FABRICATION FOR A LIGHTING DEVICE

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith. or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

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Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NECSTADT, P.C.

Richard L. Treanor

Registration No. 36,379

Tei. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 03-02)

TRADE S DEPARTMENT OF COMMERCE SERIAL NO. ATTY DOCKET NO. Form PTO 1449 PATENT AND TRADEMARY, OFFICE 09/921,895 212425US99 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT George VALLIATH **GROUP** FILING DATE August 6, 2001 2823 **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT SUB FILING DATE CLASS DATE NAME INITIAL NUMBER CLASS IF APPROPRIATE 5,528,209 06/18/96 UT Macdonald et al. UV 5,998,781 12/07/99 Vawter et al. UW 6,110,813 08/29/00 Ota et al. UX 6,452,232 B1 09/17/02 Adan 04/11/00 UY 6,049,110 Koh UΖ 5,559,368 09/24/96 Hu et al. 6,392,253 B1 05/21/02 VA Saxena VΒ 5,585,288 12/17/96 Davis et al. ٧C 5,268,327 12/07/93 Vernon VD 6,198,119 B1 03/06/01 Nabatame et al. VΕ 6,113,225 09/05/00 Miyata et al. 11/16/93 Grudkowski et al. VF 5,262,659 ۷G 6,239,012 B1 05/29/01 Kinsman 10/02/01 Wang et al VΗ 6,297,598 2002/140012 10/03/02 Droopad V١ VJ 4,866,489 09/12/89 Yokogawa et al. VΚ 6,080,378 06/27/00 Yokota et al. ٧L 5,508,554 04/16/96 Takatani et al. VM 6,477,285 B1 11/05/02 Shanley VN 09/22/87 Holder 4,695,120 03/16/99 Jewell VO 5,882,948 VΡ 5,574,589 11/12/96 Feuer et al. 5,510,665 04/23/96 Conley VQ VR 02/14/89 Akiyama 4,804,866 10/15/91 Idaka et al. 5,057,694 ٧S Pique et al. VT5,635,453 06/03/97 VU 5,719,417 02/17/98 Roeder et al. VV 5,998,819 12/07/99 Yokoyama et al. Date Considered Examiner

^{*}Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

TRADEMER'S ATTY DOCKET NO. SERIAL NO. Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE 09/921,895 212425US99 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT George VALLIATH **GROUP** FILING DATE August 6, 2001 2823 **U.S. PATENT DOCUMENTS** FILING DATE SUB **EXAMINER** DOCUMENT CLASS DATE NAME IF APPROPRIATE INITIAL NUMBER CLASS VW 2002/0079576 06/27/02 Seshan 5,148,504 09/15/92 Levi et al. VX 2002/0195610 A1 VY 12/26/02 Klosowiak ٧Z 5,477,363 12/19/95 Matsuda 05/18/99 Butler et al. WA 5,905,571 WB 5,570,226 10/29/96 Ota 02/11/92 WC 5,087,829 Ishibashi et al. WD 2001/0020278 A1 09/06/01 Saito WΕ 6,496,469 B1 12/17/02 Uchizaki WF 5,679,947 10/21/97 Doi et al. WG 11/01/01 Kadowaki et al. 2001/0036142 A1 08/29/95 Yoshida et al. WH 5,446,719 WI 5,831,960 11/03/98 Jiang et al. 12/02/97 McKee et al. WJ 5,693,140 04/23/02 WK 6,376,337 B1 Wang et al. WL 4,177,094 12/04/79 Kroon 06/01/93 WM 5,216,359 Makki et al. WN 6,307,996 B1 10/23/01 Nashimoto et al. WO 5,371,621 12/06/94 Stevens 2002/0145168 A1 10/10/02 Bojarczuk, Jr et al. WP 11/02/71 Anderson WQ 3,617,951 WR 5,838,053 11/17/98 Bevan et al. 5,684,302 11/04/97 Wersing et al. WS

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Examiner

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ATTY DOCKET NO. 212425US99

LIST OF REFERENCES CITED BY APPLICANT

EVALUATE SERIAL NO. 09/921,895

APPLICANT

George VALLIATH

FILING DATE

AUGUST 6, 2001

SERIAL NO. 09/921,895

APPLICANT

GROUP

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	FOREIGN PATENT DOCUMENTS				
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
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CBD	EP 0 860 913	08-26-95	EUROPE		
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